



Wavefront sensors and adaptive optics for optical metrology, laser and microscopy



OPTICAL
METROLOGY



HIGH-POWER
LASERS



BIO-IMAGING



X-EUV

IMAGINE OPTIC PRESENTS

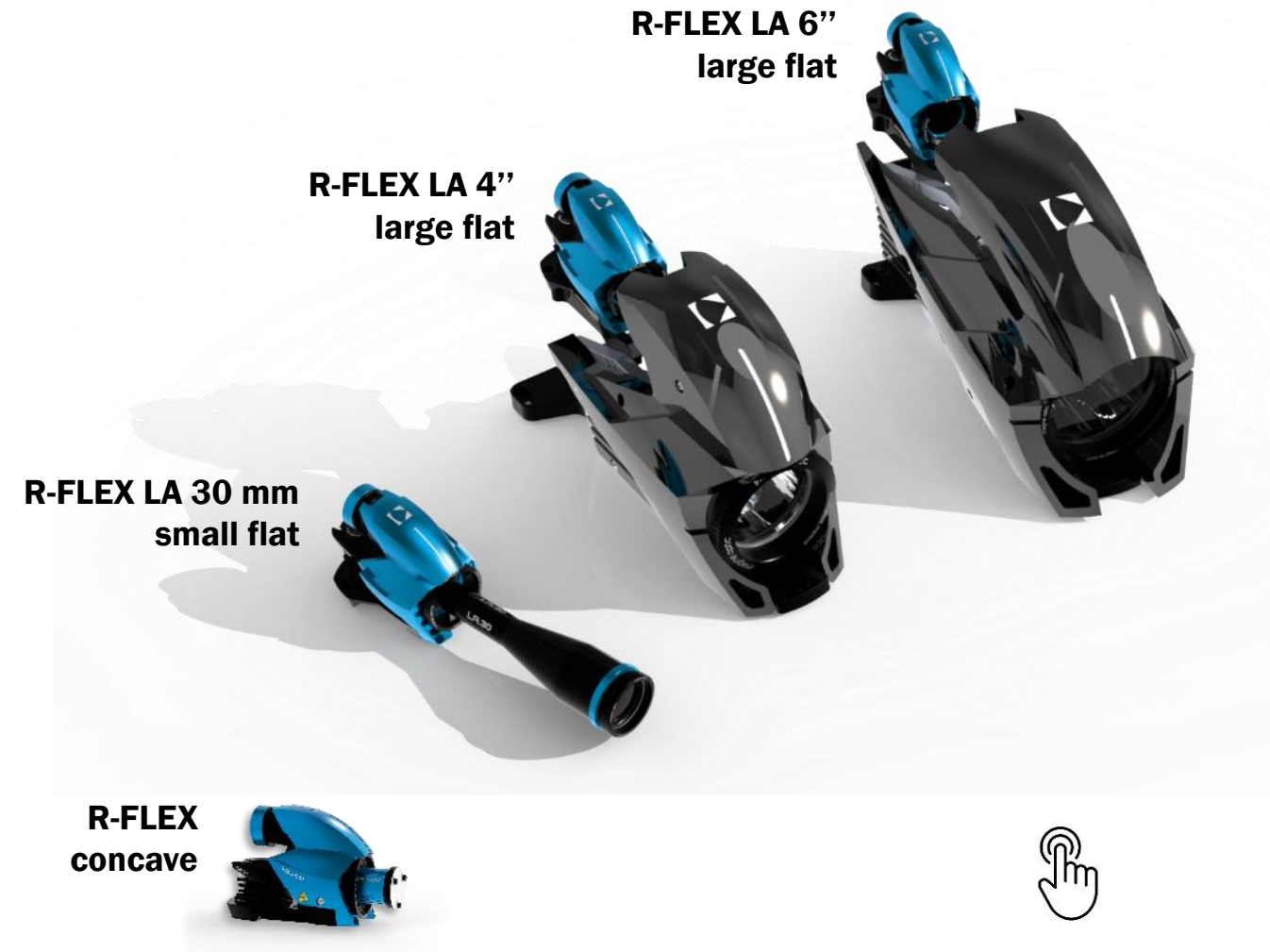
Optical metrology for AR/VR and Freeform applications



- + Founded in **1996**, development and manufacturing of **wavefront sensing & adaptive optics**
- + **55** employees, **5 M€** revenue
- + 35+ patents granted
- + > **1500 sensors** worldwide...
- + > **200 Adaptive optics** systems with Mirao52e for ophthalmology and microscopy and
> **70 adaptive optics** systems with ILAO & ILAO Star for high-power lasers in > 10 countries



R&D lab



R.FLEX
LARGE APERTURE

R.FLEX2
LARGE APERTURE SMIR

Characterization of surface form
System alignment
Characterization of lasers

Any size
Any shape
Any wavelength

High resolution
High accuracy
Large dynamic range

Insensitive to vibrations
Light & compact
Easy to use
Cost effective

manufacturing environments

+ In situ process control

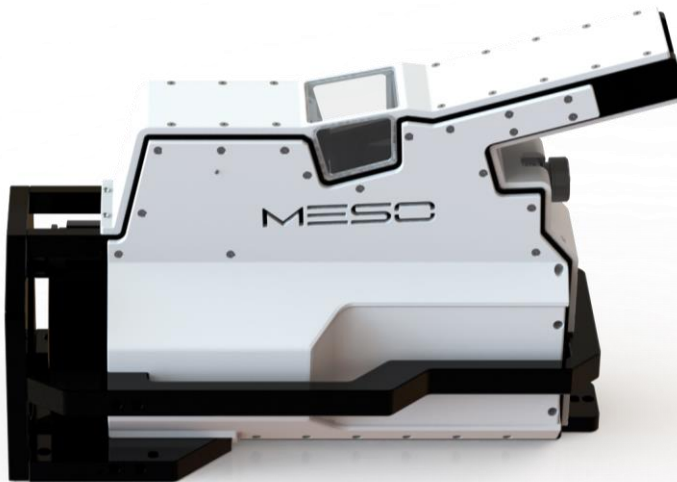
+ Thin Parallel Optics characterization

+ Transmitted wavefront quality
(TWE)

+ Surface shape & flatness
measurement (RWE)

+ Large optics testing

+ Wedge measurement

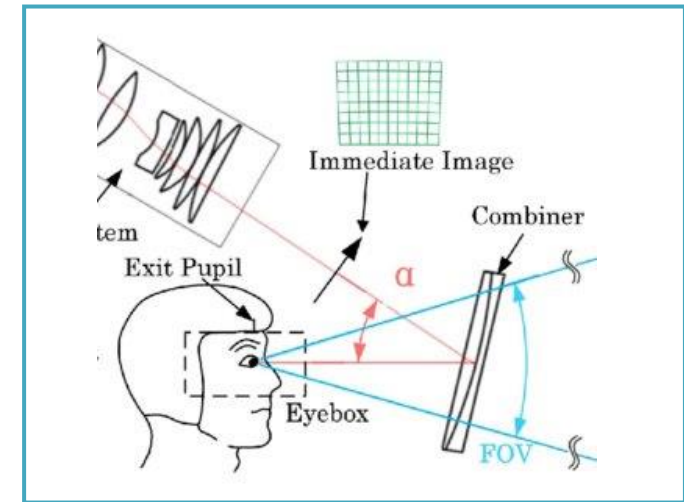


Thin Parallel Optics,
Screens,
Filters, dichroics,
Mirrors,
Beamsplitters,
Windows,
Substrates,
Crystals,
Corner cubes,
Glass wafers,
Displays,
Machined surfaces,
Prisms,
Large lenses,
Optical systems, beam expanders

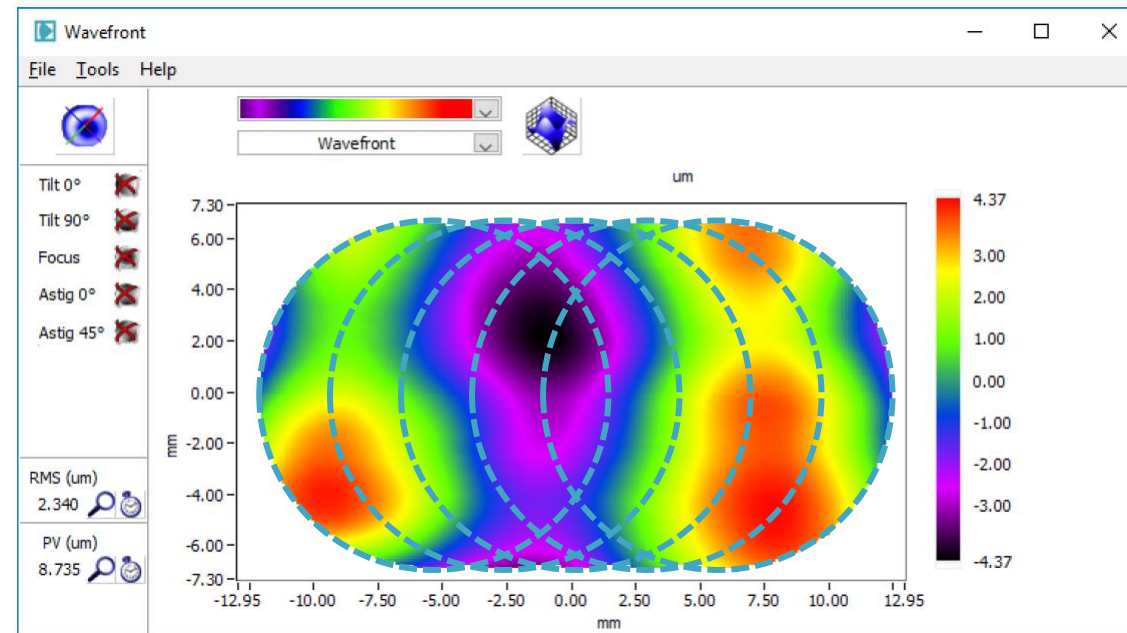
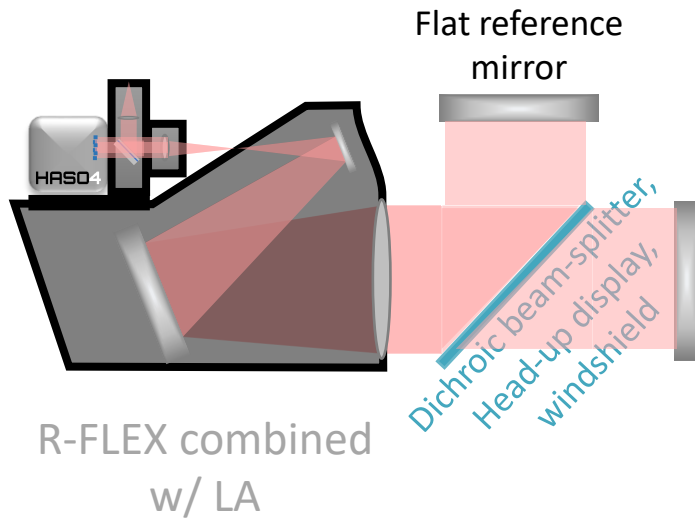


Undisturbed by
reflections from
sample back surface

Testing of Windshield embedded with thin-film in transmission & reflection

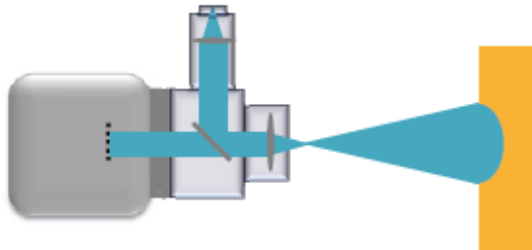


Sample diagonal ≈ 170 mm

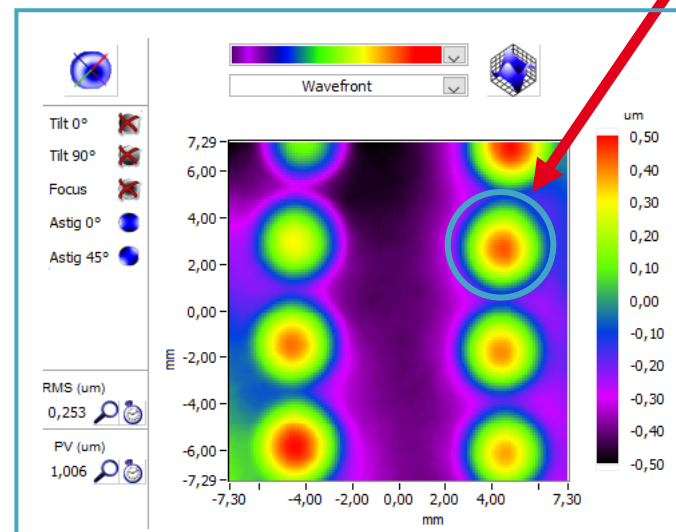


Stitched reflected wavefront

Testing of micro-structured molds

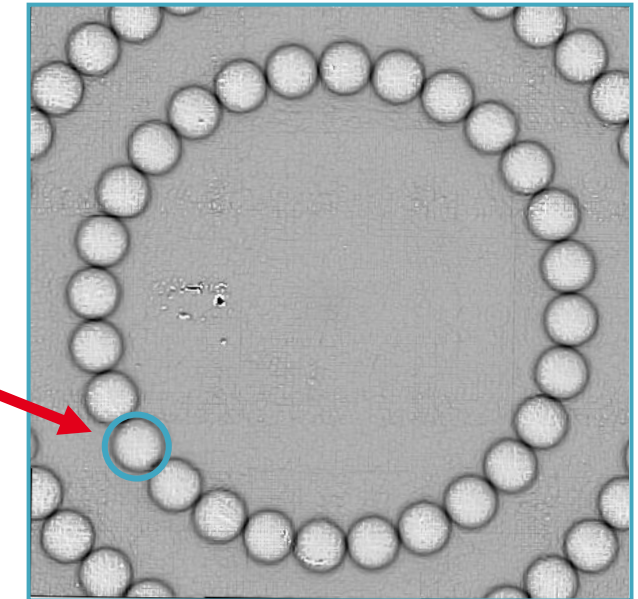


R-FLEX combined
w/ focusing module



Small area measurement

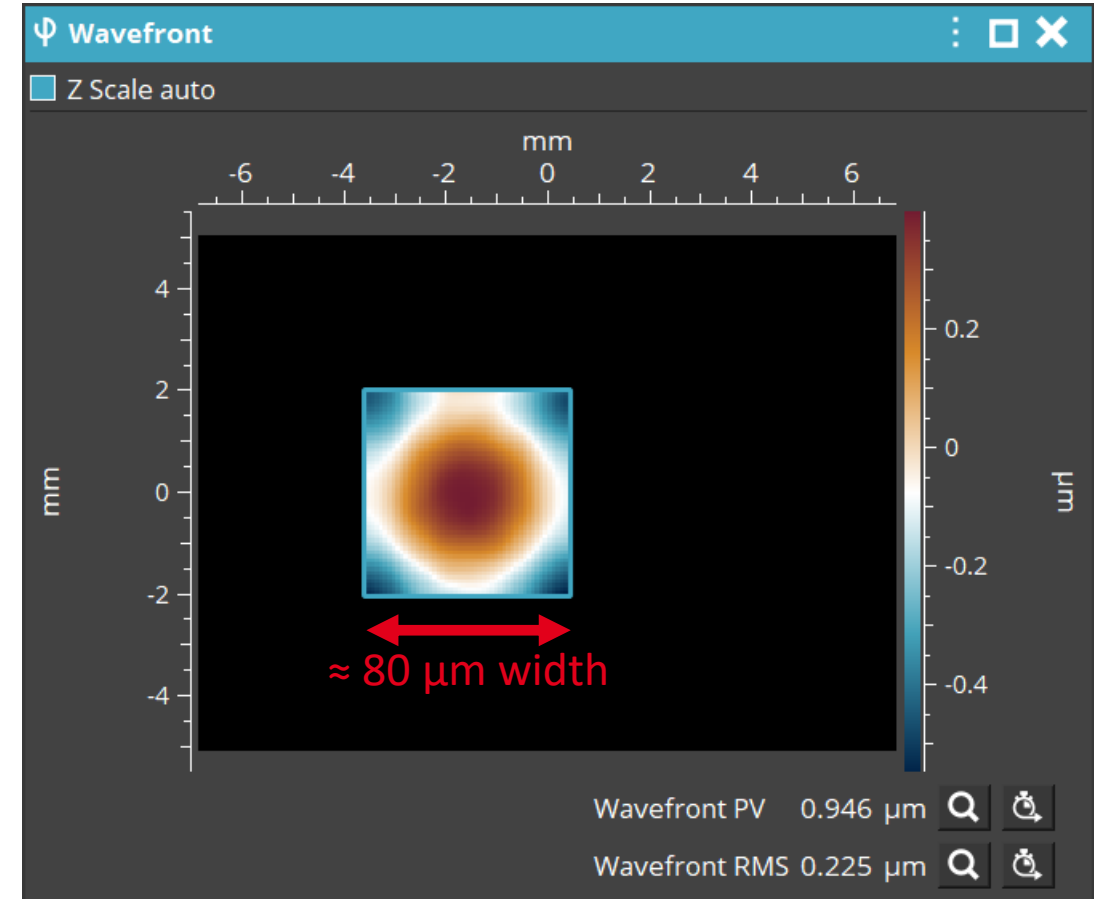
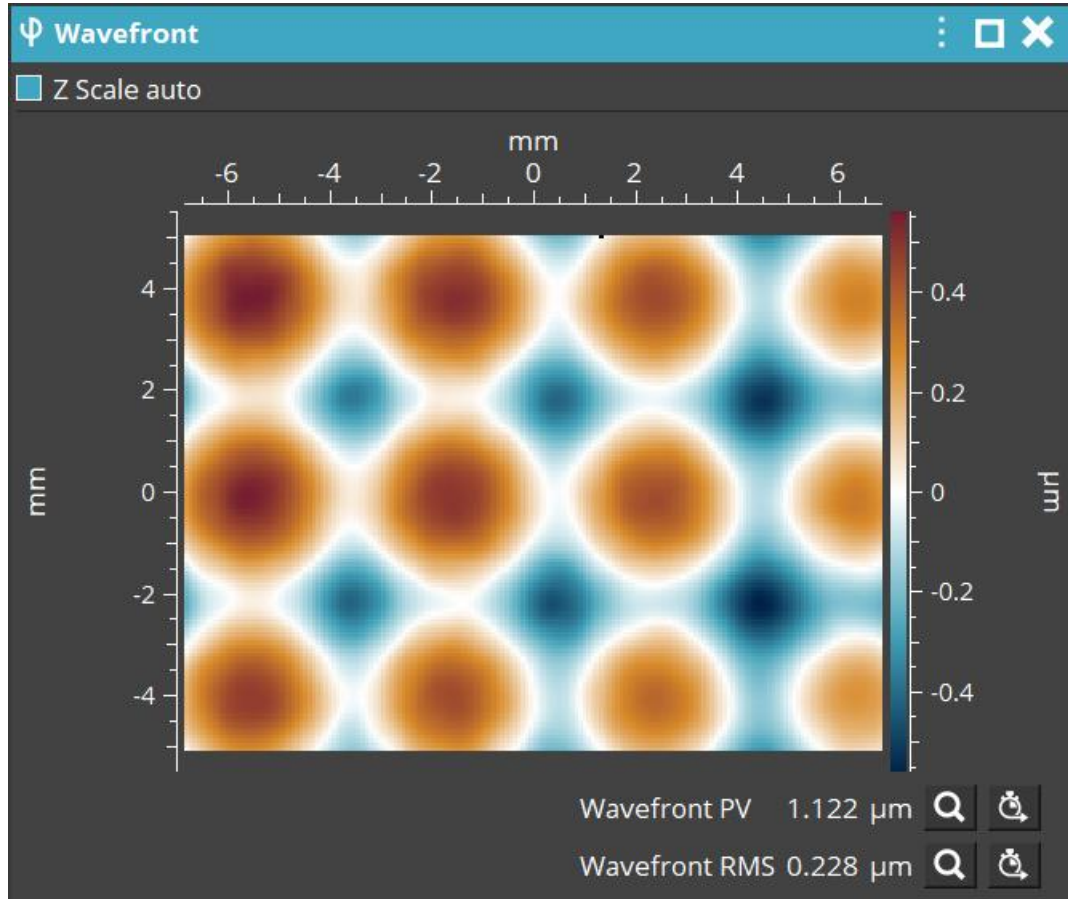
≈1mm diameter



Stitched optical power map

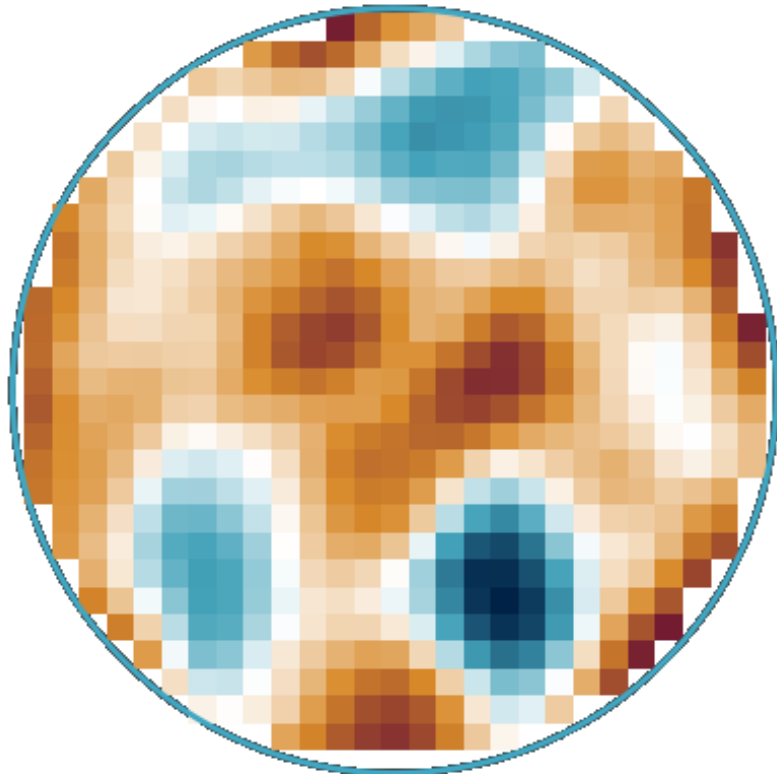
Application 3 / 4

Control of micro-optics (μL) in transmission



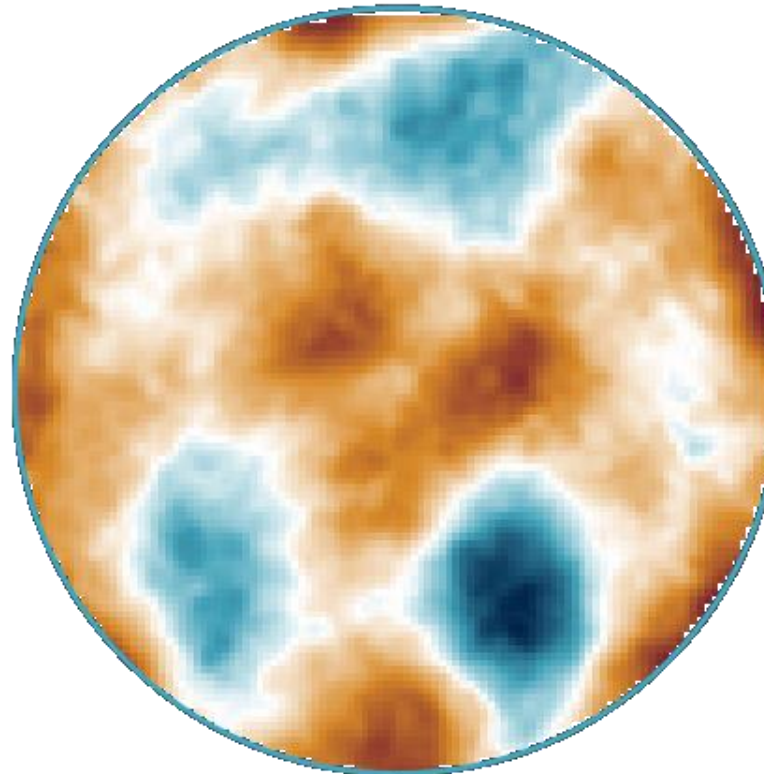
Characterization of freeform phase plate in transmission

HASO SWIR
(at 1550nm)



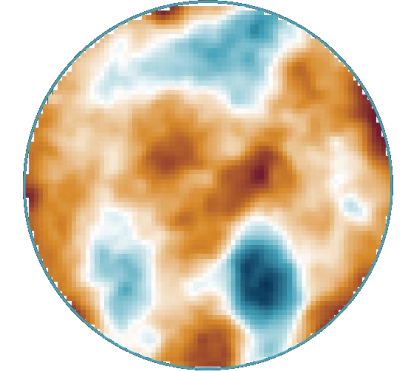
Resolution = 28 x 28
PV = 2.350 μ m,
RMS = 0.444 μ m
20 mm diameter sample

HASO LIFT SWIR
(at 1550nm)



Resolution = 112 x 112
PV = 2.552 μ m,
RMS = 0.452 μ m

HASO4 126
(at 1064nm)



PV = 2.589 μ m,
RMS = 0.460 μ m



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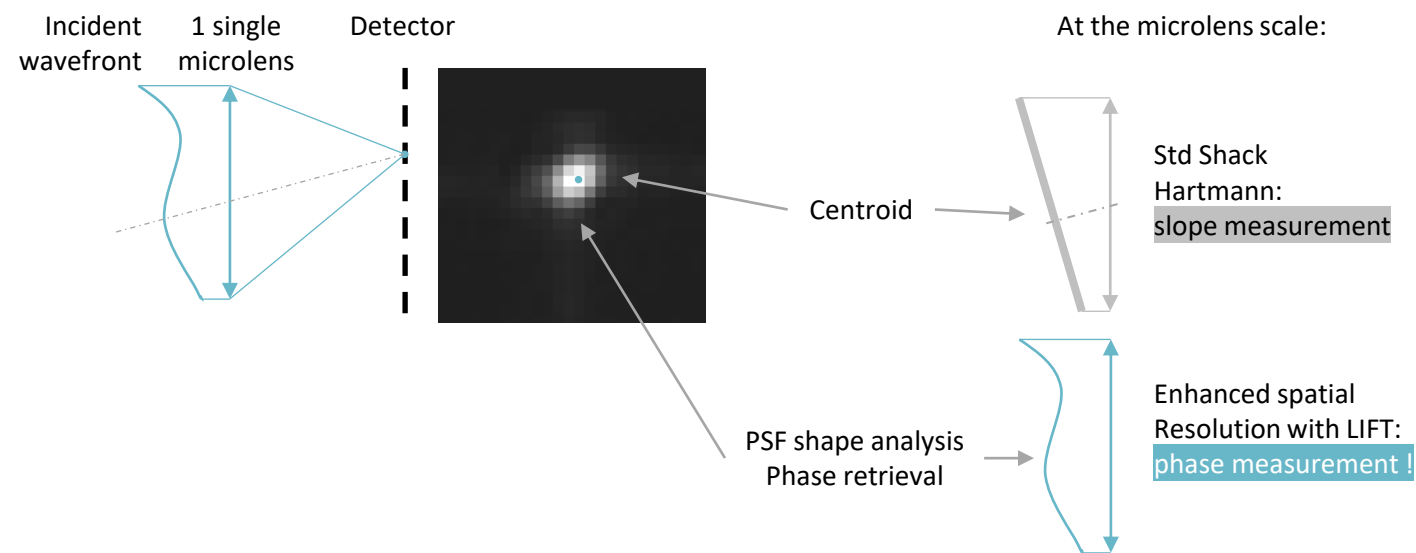
Rafael Porcar
Scientific coordinator

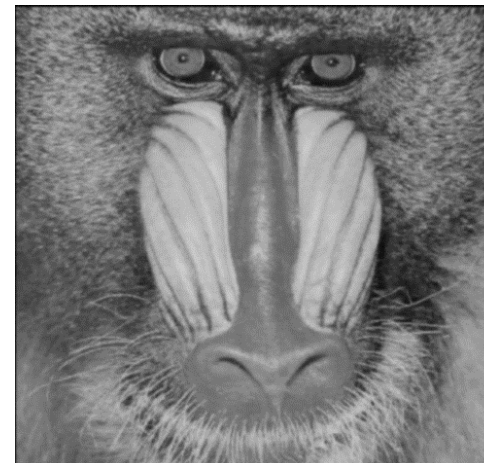
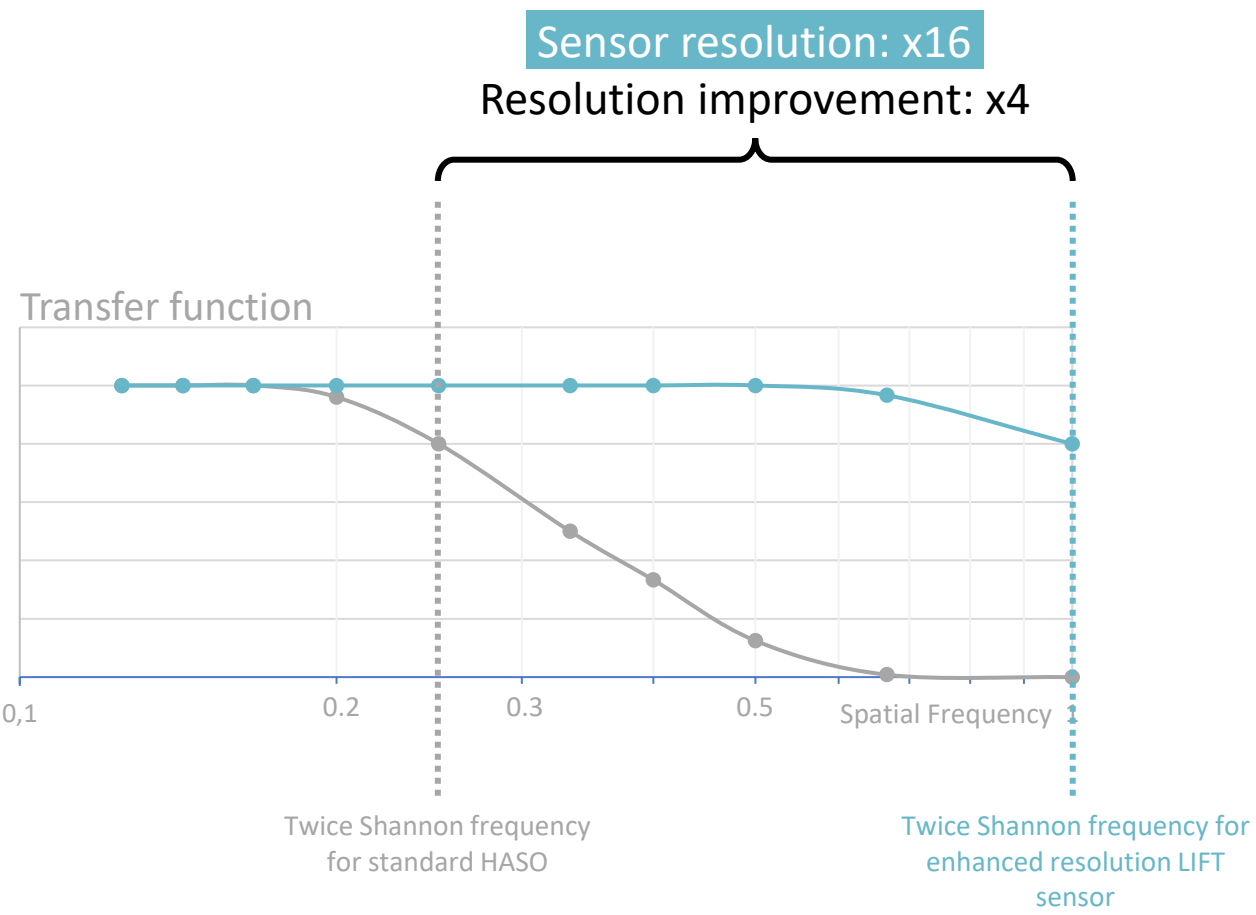
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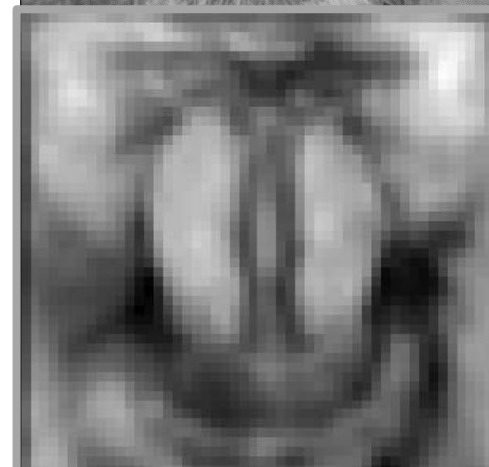
Pleased to provide more information
Happy to perform tests on your samples

Support information





Hi Res phase pattern



standard Shack Hartmann sensor
corresponding measured phase



LIFT sensor
corresponding measured phase